

**AFM and SEM investigations of ion beam synthesized Mg<sub>2</sub>Si precipitates in Si substrates**

Angelov, Christo; **Mikli, Valdek**; Amov, Blagoj; Goranova, E. Journal of optoelectronics and advanced materials 2005 / 1, p. 369-373  
[https://old.joam.inoe.ro/arkiva/pdf7\\_1/Angelov3.pdf](https://old.joam.inoe.ro/arkiva/pdf7_1/Angelov3.pdf)

**AFM characterization of the surface morphology of the severe plastic deformed copper [Electronic resource]**

Hussainova, Irina; Lõhmus, Rünno; Kommel, Lembit; Siimon, H. Proceedings of Material Research Society Spring Meeting : March 28 - April 1, 2005, San Francisco, CA, USA 2005 / [CD-ROM]

**An XPS and AFM study of polypyrrole coating on mild steel**

Idla, Katrin; Talo, A.; Niemi, H.E.-M.; Forsen, Olof; Yläsaari, Seppo Surface and interface analysis 1997 / 9, [18] p.: ill

**An XPS and AFM study of polypyrrole coating on mild steel**

Idla, Katrin; Talo, A.; Niemi, H.; Forsen, Olof; Yläsaari, Seppo 4th International Conference on Adhesion and Surface Analysis, Loughborough University, UK, April 16-18, 1996 1996 / abstract no. P27  
[https://www.researchgate.net/publication/243802279\\_An\\_XPS\\_and\\_AFM\\_study\\_of\\_polypyrrole\\_coating\\_on\\_mild\\_steel](https://www.researchgate.net/publication/243802279_An_XPS_and_AFM_study_of_polypyrrole_coating_on_mild_steel)

**Nanomechanical characterisation of materials by atomic force microscopy**

Kollo, Lauri Nanopowders, Nanostuctured Materials and Coatings : Network for Nanostructured Materials of ACC : March 17, 2005, Tallinn, Estonia : book of abstracts 2005 / p. 27

**Structural investigations of ion beam synthesized [beeta]-FeSi2**

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**Thermal annealing of sequentially deposited SnS thin films**

Safonova, Maria; Nair, Padmanabhan Pankajakshy Karunakaran; Mellikov, Enn; Aragon, Rebeca; Kerm, Karin; Naidu, Revathi; **Mikli, Valdek**; Volobujeva, Olga Proceedings of the Estonian Academy of Sciences 2015 / p. 488-494 : ill  
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**Use of atomic-force microscopy for characterization of silicon, implanted with heavy ions at high doses**

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